Session Program

2–4 Feb 2026

2nd Workshop of the CPAN Network on Instrumentation and Detectors

WG10 Characterization Techniques

CIEMAT, Salón de Actos "Margarita Salas" (Edificio 1, Planta Baja)
Avenida Complutense, 40 28040 Madrid Spain

Wednesday 4 February

10:00

WG10 Characterization Techniques

Session |

Location: CIEMAT, Salón de Actos "Margarita Salas" (Edificio 1, Planta Baja), Avenida Complutense, 40 28040 Madrid Spain |

Conveners: Dr Maria Del Carmen Jimenez Ramos, Dr Jordi Duarte Campderros

10:00–10:12 **WG10 overview**

Speakers

Dr Jordi Duarte Campderros, Dr Maria Del Carmen Jimenez Ramos

10:15–10:27

Characterization of SiC Microdosimeters for FLASH Therapy Using Ion Beam Techniques at CNA

Speaker

Jairo Antonio Villegas Dominguez

10:30–10:42

Development of a Non-Invasive Quality Control System for Semiconductor Wafer Inspection

Speaker

David Galacho Martínez

10:45–10:57

Characterizaton of Wide Band Semiconductors using Two-Photon Absorption Transient Current Technique (TPA-TCT): Methodology and Experimental Applications on SiC samples

Speaker

Cristian Quintana San Emeterio

11:00